

Business Unit & Req. # 1905 - 202420940ECCN: EAR99Total Amount: \$309,900

Note: This Sole Source Certification will become a public document, open to public inspection; therefore, you should be certain all material facts are true, relevant and clearly understandable.

SOLE SOURCE CERTIFICATION

Under the requirement of University of Florida Rule No. 6C1-3.020(5)(e)(2), the following is submitted in support of this request for authority to purchase, without bidding, the items available from only one source.

Note: Sole Source means that the item/service is unique and that the vendor is the only one from whom the item/service can be provided. Best Price alone cannot be used for sole source. If the item/service is available from more than one source of supply, best price must be determined through the competitive bid process.

A. Sole Source Vendor Company Name: Park Systems

Contact Person: Gilbert Min

Address: 3040 Olcott St, Santa Clara, CA 95054

Telephone: 2672250677

Fax: _____

Email: gmin@parksystems.com

B. Describe in lay language, what the item/service is and how it is to be used in your area of research. (cont. P2)

The HiVac PX20 is a high-vacuum atomic force microscope (AFM) equipped with scanning microwave impedance microscopy (sMIM),

C. What feature or special condition of this commodity/service is unique and cannot be obtained from any other source? Why are these features or special conditions important to the research? (cont. P2)

The HiVac PX20 offers a rare combination of high-vacuum capability with advanced AFM and sMIM, which is not available in standard commercial systems. The high-vacuum environment, capable of going to 10⁻⁵ torr from 760 torr (ambient conditions), drastically reduces noise and contamination, enabling ultra-sensitive measurements of delicate semiconductor structures.

D. Is this product being purchased directly from the manufacturer? ☒ Yes ☐ No

If No, is it available from more than one dealer?

☐ Yes ☐ No

If Yes, it is available from more than one dealer, why can this item not be bid? (cont. P2)

this is only available with park systems

E. Prior to submitting this requisition, did you investigate other possible sources? ☒ Yes ☐ No

If Yes: 1) Did you obtain quotes from the other sources? ☐ Yes ☒ No If Yes, attach copies.

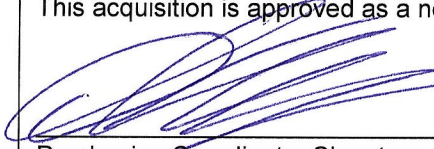
2) Is this Vendor's price lower than the other sources? ☒ Yes ☐ No If No, justify the additional cost below.

Even though this system is unique in the market, the vendor offered us a very reasonable price.

F. What efforts have been made to obtain the best price possible? Why do you feel this price is fair and reasonable? (cont. P2)

We engaged in multiple rounds of negotiation with the vendor to secure the most competitive pricing. Given the unique capabilities of the product and its limited availability in the market, the vendor has expressed a willingness to offer a favorable price.

I / We, the undersigned, certify the above to be true and correct to the best of my / our knowledge and belief and the user and / or undersigned does not have a financial interest in the above named vendor.

DEPARTMENT APPROVAL	PURCHASING APPROVAL
I hereby certify the validity of the information and feel confident the Sole Source Certification will meet University criteria and would withstand any audit or vendor protest. Istiaq firoz Shiam Digitally signed by Istiaq firoz Shiam Date: 2025.06.30 12:46:34 -04'00'	This acquisition is approved as a non-competitive purchase. 
Principal Investigator's Signature _____ Date _____	Purchasing Coordinator Signature _____ Date <u>6-30-2025</u>
FAILURE TO FILE A PROTEST IN ACCORDANCE WITH BOARD OF GOVERNORS (BOG) REGULATION 18.002 OR FAILURE TO POST THE BOND OR OTHER SECURITY AS REQUIRED IN THE BOG REGULATION 18.002 AND 18.003(3) SHALL CONSTITUTE A WAIVER OF PROTEST PROCEEDING.	<u>N.J Heredia</u> Purchasing Authorized Signature _____ Date <u>6-30-2025</u>

Sole Source Certification (Continued)

Please use the following sections to continue documentation if needed.

B. continued

which allows us to visualize nanoscale surface structures and electrical properties with extreme precision. In our semiconductor packaging research, we use it to detect buried defects, map current flow paths, and analyze material behavior at critical interfaces—tasks essential for failure analysis and device reliability improvement.

C. continued

The XY and Z scanners use piezoelectric materials and support both open- and closed-loop operation; the XY scanner must feature a 2D symmetric single-module flexure design with independent X and Y movement and a minimum scan range of 100µm.

These unique features are critical for our research, as it allows precise characterization of nanoscale defects and interfaces that are otherwise undetectable in ambient conditions.

D. continued

E. continued

F. continued

They recognize that placement of their system at the University of Florida would serve as a strong marketing and branding opportunity, enhancing their visibility and reputation within the research community.